

<b>Notice of References Cited</b>	Application/Control No. 10/023,871	Applicant(s)/Patent Under Reexamination WAKAI ET AL.	
	Examiner Tan Dean D. Nguyen	Art Unit 3689	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-5,758,328	05-1998	Giovannoli, Joseph	705/26
	C	US-			
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	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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